SN74ALS29841 10-BIT BUS-INTERFACE D-TYPE LATCH WITH 3-STATE OUTPUTS

SDAS149A - JUNE 1988 - REVISED JANUARY 1995

 3-State Buffer-Type Outputs Drive Bus Lines Directly 	DW OR NT PACKAGE (TOP VIEW)	
Bus-Structured Pinout	OE (1 24) V _{CC}	
 Provides Extra Bus-Driving Latches 	1D 2 23 1Q	
Necessary for Wider Address/Data Paths or	2D 🛛 3 22 🗍 2Q	
Buses With Parity	3D 🛛 4 21 🗍 3Q	
 Buffered Control Inputs Reduce dc Loading 	4D 🛛 5 20 🗍 4Q	
Effects	5D 🛛 6 19 🗍 5Q	
Power-Up High-Impedance State	6D 🛛 7 18 🗍 6Q	
Package Options Include Plastic	7D 🛮 8 17 🗓 7Q	
Small-Outline (DW) Packages and Standard	8D 🛮 9 16 🕽 8Q	
Plastic (NT) 300-mil DIPs	9D 🛛 10 15 🗍 9Q	
	10D 🛛 11 14 🗍 10Q	
description	GND [12 13] LE	

This 10-bit latch features 3-state outputs designed

specifically for driving highly capacitive or relatively low-impedance loads. It is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The ten latches are transparent D-type latches. The SN74ALS29841 has noninverting data (D) inputs.

A buffered output-enable (\overline{OE}) input can place the ten outputs in either a normal logic state (high or low logic levels) or in a high-impedance state. The outputs also are in the high-impedance state during power-up and power-down conditions. The outputs remain in the high-impedance state while the device is powered down. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operation of the latches. Old data can be retained or new data can be entered while the outputs are off.

The SN74ALS29841 is characterized for operation from 0°C to 70°C.

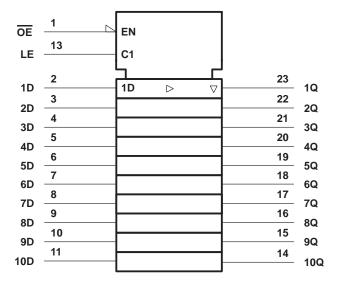
FUNCTION TABLE

	INPUTS	OUTPUT	
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q ₀
Н	X	Χ	Z



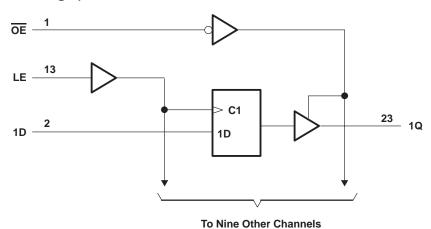
SDAS149A – JUNE 1988 – REVISED JANUARY 1995

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range	−65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
V _{IL}	Low-level input voltage			0.8	V
IOH	High-level output current			-24	mA
l _{OL}	Low-level output current			48	mA
t _W	Pulse duration, LE high	6			ns
t _{su}	Setup time, data before LE↓	2.5			ns
t _h	Hold time, data after LE↓	4.5			ns
TA	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
VIK	$V_{CC} = 4.75 V$,	$I_{ } = -18 \text{ mA}$			-1.2	V
Veri	\\aa - 4.75.\\	$I_{OH} = -15 \text{ mA}$	2.4	3.3		V
VOH	V _{CC} = 4.75 V	$I_{OH} = -24 \text{ mA}$	2	3.1		٧
V _{OL}	$V_{CC} = 4.75 V$,	$I_{OL} = 48 \text{ mA}$		0.35	0.5	V
lozн	$V_{CC} = 5.25 V$,	V _O = 2.7 V			20	μΑ
lozL	$V_{CC} = 5.25 V$,	V _O = 0.4 V			-20	μΑ
lį	$V_{CC} = 5.25 V$,	V _I = 5.5 V			0.1	mA
lін	V _{CC} = 5.25 V,	V _I = 2.7 V			20	μΑ
I _I L	V _{CC} = 5.25 V,	V _I = 0.4 V			-0.2	mA
los [‡]	V _{CC} = 5.25 V,	V _O = 0	-75		-250	mA
^I CC	V _{CC} = 5.25 V,	Outputs low		55	85	mA

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

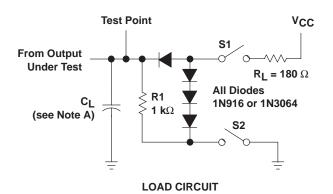
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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	I TEST CONDITIONS		to MAX [†] , o MAX [†]	UNIT		
	(INFOT)	(001701)		MIN	MAX			
t _{PLH}	D	A O	0 50 -5	2	9.5	ns		
^t PHL	Б	Any Q	C _L = 50 pF	2	9.5	115		
^t PLH	D	A O	0. 200 = 5		14	ns		
^t PHL	Б	Any Q	C _L = 300 pF		14	115		
^t PLH		A O	0. 50.55		12	ns		
^t PHL	LL	Any Q	Any Q	LE Any Q C _L = 50	C _L = 50 pF		12	115
^t PLH	LE	Any	C. 200 pF		16	ns		
^t PHL		Any Q	C _L = 300 pF		16	113		
^t PZH	ŌĒ	Any O			14	ns		
t _{PZL}	ÜE	Any Q	Any Q	OL Ally Q	C _L = 50 pF		14	115
^t PZH	ŌĒ				20	ns		
t _{PZL}		Any Q	C _L = 300 pF		23	115		
^t PHZ	ŌĒ	Am. 0	0 50 -5		15	ns		
t _{PLZ}		Any Q	C _L = 50 pF		12	113		
^t PHZ	ŌĒ	Any O	C 5 pE		9	ns		
t _{PLZ}	OE	Any Q	С _L = 5 pF		9	113		

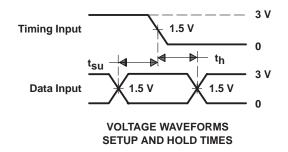
[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

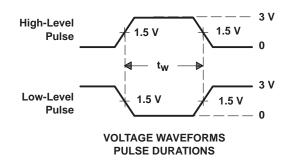
PARAMETER MEASUREMENT INFORMATION

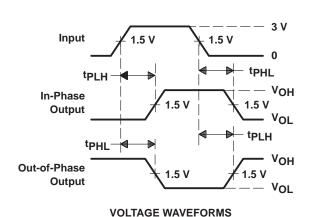


SWITCH POSITION TABLE				
TEST	S1	S2		
[†] PLH [†] PHL [†] PZH [†] PZL [†] PHZ [†] PI 7	Closed Closed Open Closed Closed Closed	Closed Closed Closed Open Closed Closed		

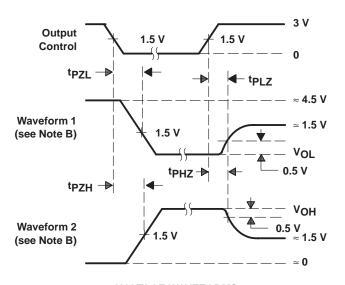
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PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq 2.5$ ns, $t_f \leq 2.5$ ns.

Figure 1. Load Circuit and Voltage Waveforms



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